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1 A semiconductor chip of the present invention includes a plurality of first
2 elements each of which diagnoses itself, and a second element which inputs diagnosis
3 results from the first elements and determines whether or not there is a faulty first
4 element in the first elements. A method of the present invention which is performed in
5 a semiconductor chip including a plurality of first elements, includes diagnosing the first
6 elements by itself; and determining whether or not there is a faulty first element in the
7 first elements based on diagnosis results from the first elements.